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A Low-Energy Electron Microscope for the Study of Growth and Dynamics of Surfaces in Spain

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Low-energy electron microscopy (LEEM) is a full-view non-scanning technique in which a beam of low-energy electrons that has interacted with a sample is imaged. The technique characterizes the sample's surface in real-space with nanometer-scale lateral resolution. The ability to acquire images at a fraction of a second during temperature changes, while depositing films and exposing materials to reactive gases makes LEEM invaluable for studying dynamical processes on surfaces. The first pure-electron LEEM microscope in Spain is being installed at the Instituto de Química Física "Rocasolano" in Madrid. The goal of this talk is to provide an introduction to the capabilities of this instrument through examples taken from our published work, so it can benefit the spanish research community.

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